

February 1992 Revised June 2001

# 74LVQ244

# Low Voltage Octal Buffer/Line Driver with 3-STATE Outputs

### **General Description**

The LVQ244 is an octal buffer and line driver designed to be employed as a memory address driver, clock driver and bus oriented transmitter or receiver which provides improved PC board density.

#### **Features**

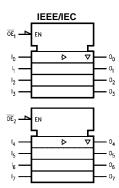
- Ideal for low power/low noise 3.3V applications
- Implements patented EMI reduction circuitry
- Available in SOIC JEDEC, SOIC EIAJ and QSOP packages
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Improved latch-up immunity
- $\blacksquare$  Guaranteed incident wave switching into 75  $\!\Omega$
- 4 kV minimum ESD immunity

# **Ordering Code:**

Order Number	Package Number	Package Description
74LVQ244SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide
74LVQ244SJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74LVQ244QSC	MQA20	20-Lead Quarter Size Outline Package (QSOP), JEDEC MO-137, 0.150" Wide

Device also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code.

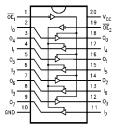
# **Logic Symbol**



## **Pin Descriptions**

Pin Names	Description				
$\overline{OE}_1$ , $\overline{OE}_2$	3-STATE Output Enable Inputs				
I <sub>0</sub> -I <sub>7</sub>	Inputs				
O <sub>0</sub> -O <sub>7</sub>	Outputs				

# **Connection Diagram**



#### **Truth Tables**

Inputs		Outputs		
OE <sub>1</sub>	I <sub>n</sub>	(Pins 12, 14, 16, 18)		
L	L	L		
L	Н	Н		
Н	Χ	Z		

Inputs		Outputs
OE <sub>2</sub>	In	(Pins 3, 5, 7, 9)
L	L	L
L	Н	Н
Н	X	Z

H = HIGH Voltage Level L = LOW Voltage Level X = Immaterial Z = High Impedance

# **Absolute Maximum Ratings**(Note 1)

## **Recommended Operating** Conditions (Note 2)

Supply Voltage ( $V_{CC}$ )

Output Voltage (V<sub>O</sub>)

Operating Temperature (T<sub>A</sub>)

 $V_{\text{IN}}$  from 0.8V to 2.0V

Minimum Input Edge Rate  $\Delta V/\Delta t$ 

Input Voltage (V<sub>I</sub>)

V<sub>CC</sub> @ 3.0V

-0.5V to +7.0V Supply Voltage (V<sub>CC</sub>) DC Input Diode Current (I<sub>IK</sub>)

 $V_{I} = -0.5V$ -20 mA  $V_I = V_{CC} + 0.5V$ +20 mA

DC Input Voltage (V<sub>I</sub>) -0.5V to  $V_{CC} + 0.5V$ 

DC Output Diode Current (I<sub>OK</sub>)

 $V_O = -0.5V$ -20 mA  $V_O = V_{CC} + 0.5V$ +20 mA

DC Output Voltage (V<sub>O</sub>) -0.5V to  $V_{CC} + 0.5V$ 

DC Output Source

or Sink Current (I<sub>O</sub>)  $\pm 50 \text{ mA}$ 

DC V<sub>CC</sub> or Ground Current

±400 mA  $(I_{CC} \mbox{ or } I_{GND})$ 

Storage Temperature (T<sub>STG</sub>)  $-65^{\circ}C$  to  $+150^{\circ}C$ 

DC Latch-Up Source or

Sink Current

Note 1: The "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the Electrical Characteristics tables are not guaranteed at the absolute maximum ratings. The "Recommended Operating Conditions" table will define the conditions for actual device operation.

2.0V to 3.6V

0V to V<sub>CC</sub>

0V to V<sub>CC</sub>

125 mV/ns

 $-40^{\circ}C$  to  $+85^{\circ}C$ 

Note 2: Unused inputs must be held HIGH or LOW. They may not float.

#### **DC Electrical Characteristics**

Symbol	Parameter	v <sub>cc</sub>	$T_A = +25^{\circ}C$		$T_A = -40^{\circ}C$ to $+85^{\circ}C$	Units	Conditions	
Symbol	r ai ailletei	(V)	Тур	Gua	Guaranteed Limits			
V <sub>IH</sub>	Minimum High Level	3.0	1.5	2.0	2.0	V	V <sub>OUT</sub> = 0.1V	
	Input Voltage						or V <sub>CC</sub> – 0.1V	
V <sub>IL</sub>	Maximum Low Level	3.0	1.5	0.8	0.8	V	V <sub>OUT</sub> = 0.1V	
	Input Voltage	3.0					or V <sub>CC</sub> – 0.1V	
V <sub>OH</sub>	Minimum High Level	3.0	2.99	2.9	2.9	V	$I_{OUT} = -50 \mu A$	
	Output Voltage	3.0		2.58	2.48	V	$V_{IN} = V_{IL}$ or $V_{IH}$ (Note 3)	
		3.0		2.36	2.40	v	$I_{OH} = -12 \text{ mA}$	
V <sub>OL</sub>	Maximum Low Level	3.0	0.002	0.1	0.1	V	I <sub>OUT</sub> = 50 μA	
	Output Voltage	3.0		0.36	0.44	V	$V_{IN} = V_{IL}$ or $V_{IH}$ (Note 3)	
		0.0		0.00	0.44	•	$I_{OL} = 12 \text{ mA}$	
I <sub>IN</sub>	Maximum Input Leakage Current	3.6		±0.1	±1.0	μΑ	$V_I = V_{CC}$ , GND	
I <sub>OLD</sub>	Minimum Dynamic (Note 4)	3.6			36	mA	V <sub>OLD</sub> = 0.8V Max (Note 5)	
I <sub>OHD</sub>	Output Current	3.6			-25	mA	V <sub>OHD</sub> = 2.0V Min (Note 5)	
I <sub>CC</sub>	Maximum Quiescent	3.6		4.0	40.0	μА	$V_{IN} = V_{CC}$	
	Supply Current	0.0					or GND	
l <sub>OZ</sub>	Maximum 3-STATE						$V_{I}(\overline{OE}) = V_{IL}, V_{IH}$	
	Leakage Current	3.6		±0.25	±2.5	μΑ	$V_I = V_{CC}$ , GND	
							$V_O = V_{CC}$ , GND	
V <sub>OLP</sub>	Quiet Output Maximum Dynamic V <sub>OI</sub>	3.3	0.4	0.8		٧	(Note 6)(Note 7)	
V <sub>OLV</sub>	Quiet Output							
· OLV	Minimum Dynamic V <sub>OL</sub>	3.3	-0.4	-0.8		V	(Note 6)(Note 7)	
V <sub>IHD</sub>	Minimum High Level Dynamic Input Voltage	3.3	1.7	2.0		V	(Note 6)(Note 8)	
V <sub>ILD</sub>	Maximum Low Level Dynamic Input Voltage	3.3	1.7	0.8		٧	(Note 6)(Note 8)	

±300 mA

Note 3: All outputs loaded thresholds on input associated with output under test.

Note 4: Maximum test duration 2.0 ms, one output loaded at a time.

Note 5: Incident wave switching on transmission lines with impedances as low as  $75\Omega$  for commercial temperature range is guaranteed for 74LVQ.

Note 6: Worst case package.

Note 7: Max number of outputs defined as (n). Data inputs are driven 0V to 3.3V; one output at GND.

Note 8: Max number of Data Inputs (n) switching. (n-1) inputs switching 0V to 3.3V. Input-under-test switching: 3.3V to threshold  $(V_{ILD})$ , 0V to threshold  $(V_{IHD})$ , f = 1 MHz.

# **AC Electrical Characteristics**

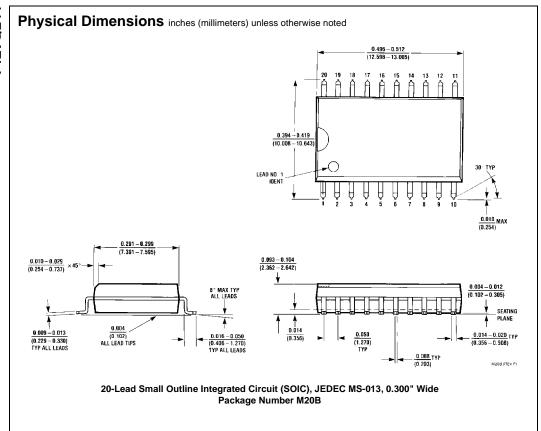
				$T_A = +25^{\circ}C$		T <sub>A</sub> = -40°	C to +85°C	
Symbol Parameter		V <sub>CC</sub>	$V_{CC}$ $C_L = 50 \text{ pF}$			$C_L = 50 \text{ pF}$		Units
		(V)	Min	Тур	Max	Min	Max	
t <sub>PHL</sub>	Propagation Delay	2.7	2.0	8.4	12.7	2.0	14.0	ns
t <sub>PLH</sub>	Data to Output	$3.3\pm0.3$	2.0	7.0	9.0	2.0	9.5	115
t <sub>PZL</sub>	Output Enable Time	2.7	2.5	9.6	16.9	2.5	18.0	ns
$t_{PZH}$		$3.3\pm0.3$	2.5	8.0	12.0	2.5	12.5	115
t <sub>PHZ</sub>	Output Disable Time	2.7	1.0	10.8	19.0	1.0	20.0	
$t_{PLZ}$		$3.3 \pm 0.3$	1.0	9.0	13.5	1.0	14.0	ns
toshl	Output to Output	2.7		1.0	1.5		1.5	
t <sub>OSLH</sub>	Skew Data to Output (Note 9)	$3.3\pm0.3$		1.0	1.5		1.5	ns

Note 9: Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH-to-LOW (t<sub>OSHL</sub>) or LOW-to-HIGH (t<sub>OSLH</sub>). Parameter guaranteed by design.

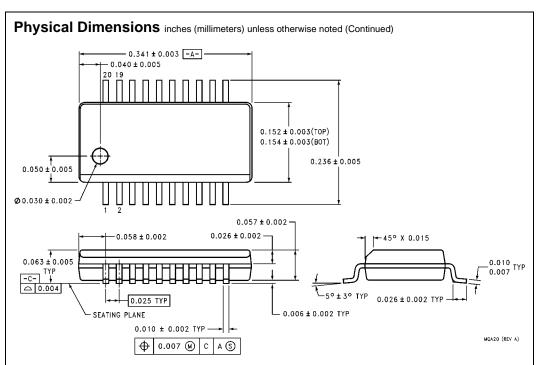
# Capacitance

Symbol	Parameter	Тур	Units	Conditions
C <sub>IN</sub>	Input Capacitance	4.5	pF	V <sub>CC</sub> = Open
C <sub>PD</sub> (Note 10)	Power Dissipation Capacitance	70	pF	$V_{CC} = 3.3V$

Note 10: C<sub>PD</sub> is measured at 10 MHz.



# Physical Dimensions inches (millimeters) unless otherwise noted (Continued) 12.6±0.10 0.40 TYP --A-5.3±0.10 9.27 TYP 7.8 -B-3.9 0.2 C B A ALL LEAD TIPS 10 PIN #1 IDENT.-0.6 TYP 1.27 TYP LAND PATTERN RECOMMENDATION ALL LEAD TIPS SEE DETAIL A 0.1 C 1.8±0.1 -C-L <sub>0.15±0.05</sub> 0.15-0.25 -1.27 TYP 0.35-0.51 ⊕ 0.12 **(** C A DIMENSIONS ARE IN MILLIMETERS GAGE PLANE 0.25 NOTES: A. CONFORMS TO EIAJ EDR-7320 REGISTRATION, ESTABLISHED IN DECEMBER, 1998. B. DIMENSIONS ARE IN MILLIMETERS. C. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS. 0.60±0.15 SEATING PLANE 1.25 -M20DRevB1 DETAIL A 20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide Package Number M20D



20-Lead Quarter Size Outline Package (QSOP), JEDEC MO-137, 0.150" Wide Package Number MQA20

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